74HC573; 74HCT573

Octal D-type transparent latch; 3-state

1. General Description

The 74HC573; 74HCT573 is an 8-bit D-type transparent latch with 3-state outputs. The device features latch enable (LE) and output enable ($\overline{OE}$) inputs. When LE is HIGH, data at the inputs enter the latches. In this condition the latches are transparent, a latch output will change each time its corresponding D-input changes. When LE is LOW the latches store the information that was present at the inputs a set-up time preceding the HIGH-to-LOW transition of LE. A HIGH on $\overline{OE}$ causes the outputs to assume a high-impedance OFF-state. Operation of the $\overline{OE}$ input does not affect the state of the latches. Inputs include clamp diodes. This enables the use of current limiting resistors to interface inputs to voltages in excess of V_{CC}.

2. Features and Benefits

■ Wide operating voltage 2.0 V to 6.0 V

■ High noise immunity

■ CMOS low power dissipation

■ Latch-up performance exceeds 250 mA

■ Input levels:

- For 74HC573: CMOS level
- For 74HCT573: TTL level

■ Inputs and outputs on opposite sides of package allowing easy interface with microprocessors

■ Useful as input or output port for microprocessors and microcomputers

■ 3-state non-inverting outputs for bus-oriented applications

■ Common 3-state output enable input

■ Complies with JEDEC standards:

- JESD8C (2.7 V to 3.6 V)
- JESD7A (2.0 V to 6.0 V)

■ ESD protection:

- HBM JESD22-A114F exceeds 2000 V
- MM JESD22-A115-A exceeds 200 V

■ Multiple package options

■ Specified from -40 °C to +85 °C and from -40 °C to +125 °C

3. Ordering Information

Table 1. Ordering information

Type number	Package		
	Name	**Description**	**Quantity**
74HC573D	SOP-20L	plastic small outline package; 20 leads; body width 7.5 mm	2000
74HCT573D			
74HC573PW	TSSOP20L	plastic thin shrink small outline package; 20 leads; body width 4.4 mm	2500
74HCT573PW			

4.Function Diagram

Fig. 1.   Logic diagram

Fig. 2.   Functional diagram

Fig. 3.   Logic symbol

Fig. 4.   IEC logic symbol
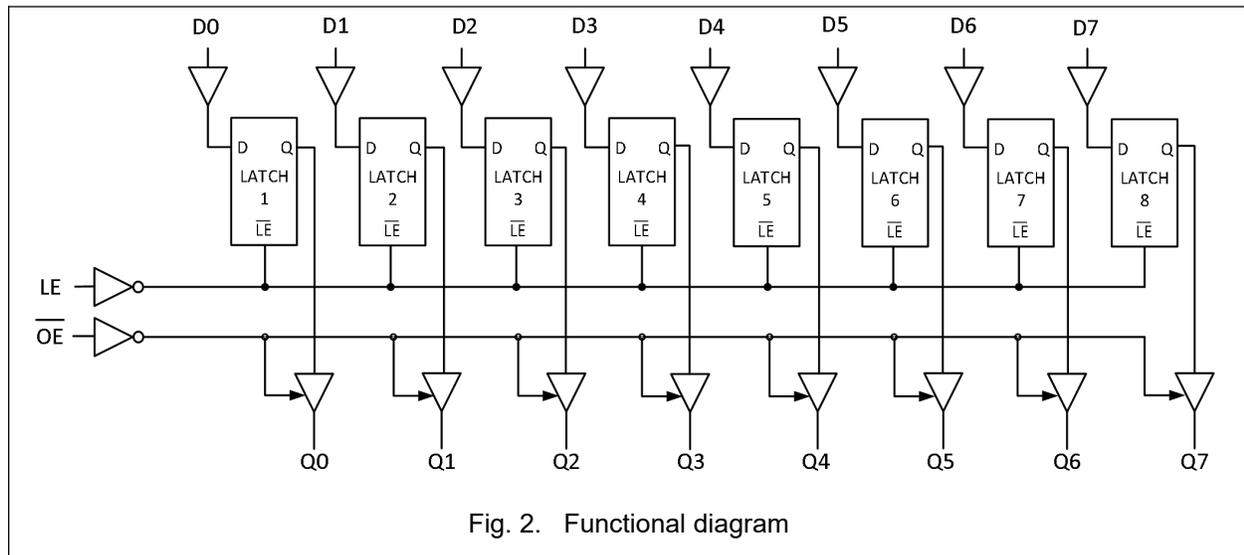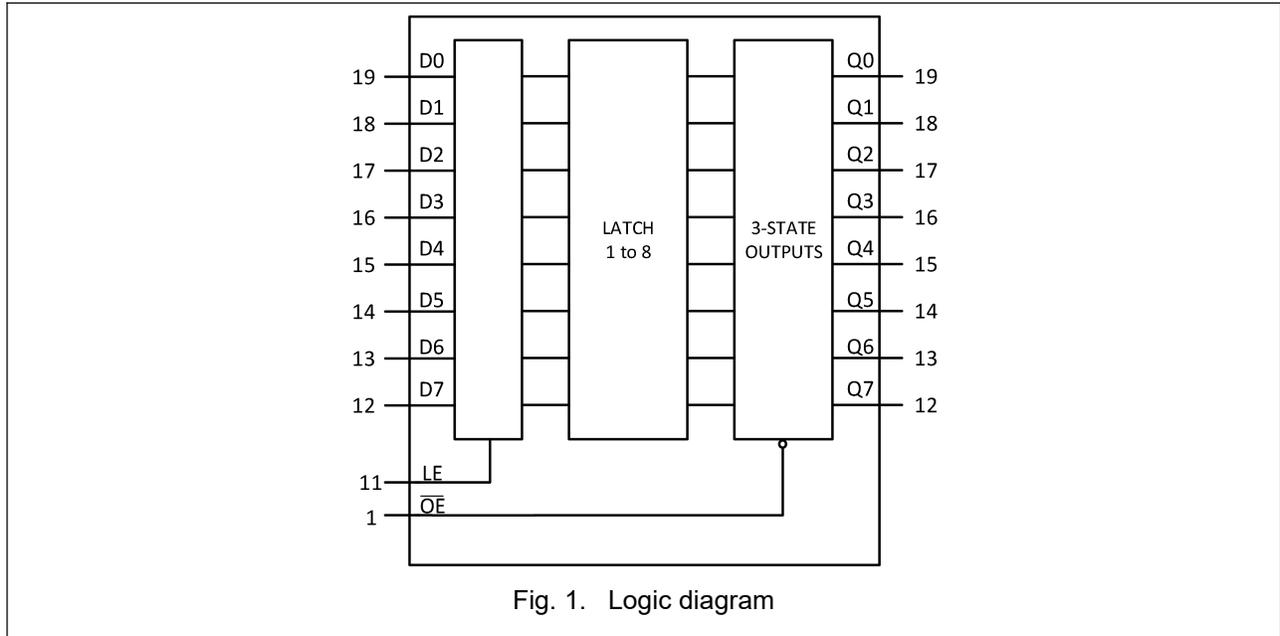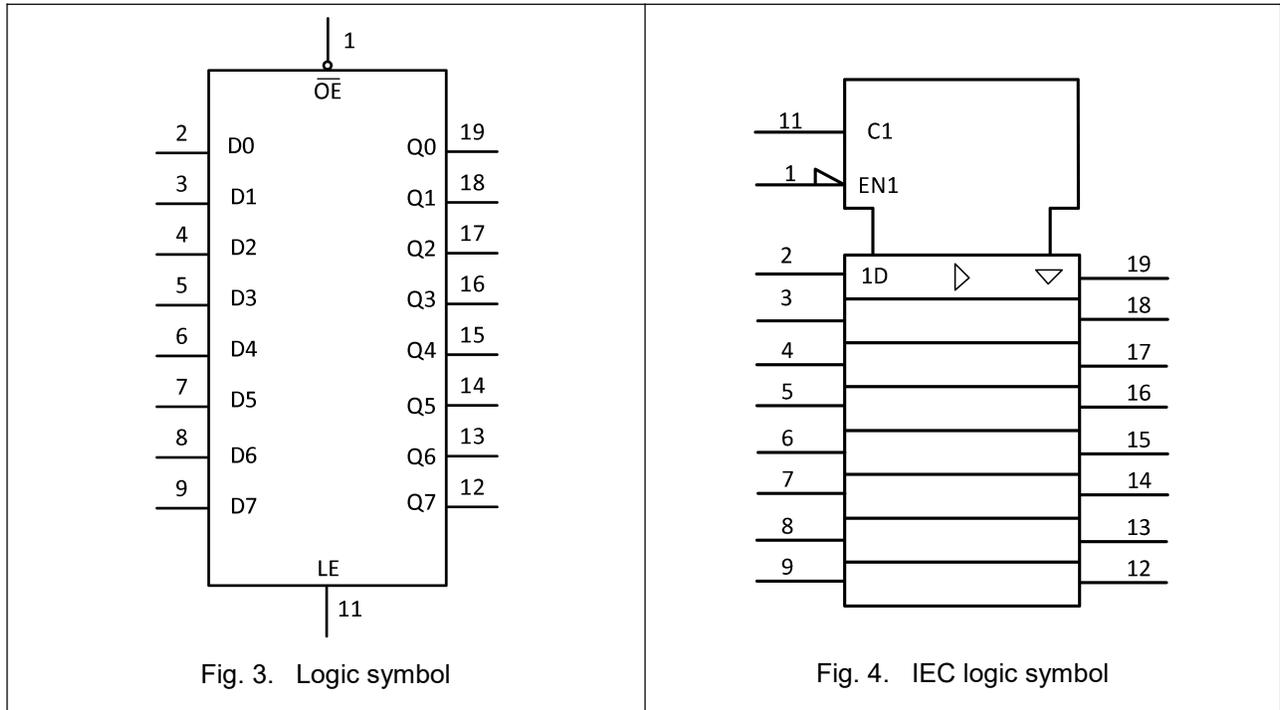
5.Pinning Information

5.1.   Pinning

Fig. 5. Top view pin configuration SOP-20L and TSSOP-20L

5.2. Pin description

Table 2. Pin description

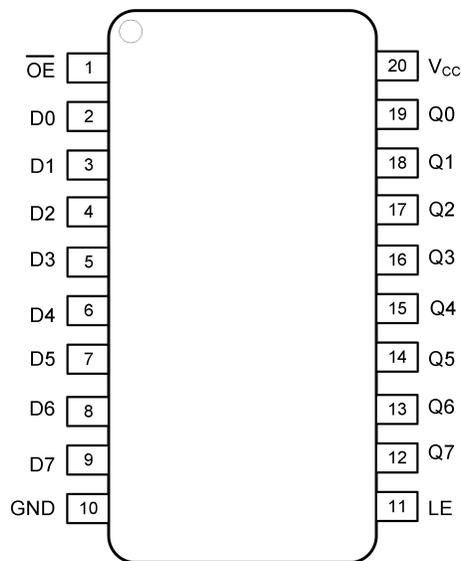| Symbol	Pin	Description
$\overline{OE}$	1	3-state output enable input (active LOW)
Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7	19,18,17,16,15,14,13,12	3-state latch output
D0, D1, D2, D3, D4, D5, D6, D7	2, 3, 4, 5, 6, 7, 8, 9	data input
GND	10	ground (0 V)
LE	11	latch enable input (active HIGH)
V_{CC}	20	supply voltage

6.Functional Description

Table 3. Function table

H = HIGH voltage level; h = HIGH voltage level one set-up time prior to the LOW-to-HIGH clock transition; L = LOW voltage level; l = LOW voltage level one set-up time prior to the LOW-to-HIGH clock transition; Z = high-impedance OFF-state.

Operating modes	Control		Input	Internal latches	Outputs
	$\overline{OE}$	LE	Dn		Qn
Enable and read register (transparent mode)	L	H	L	L	L
			H	H	H
Latch and read register	L	L	l	L	L
			h	H	H
Latch register and disable outputs	H	L	l	L	Z
			h	H	Z

7. Absolute Maximum Ratings

Stresses exceeding the absolut`e maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Table 5. Absolute Maximum Ratings
In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND.

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	7	V
I_{IK}	input clamping current	V_I < -0.5 V or V_I > V_{CC} + 0.5 V		±20	mA
I_{OK}	output clamping current	V_O < -0.5 V or V_O > V_{CC} + 0.5 V		±20	mA
I_O	output current	-0.5V < V_O < V_{CC} + 0.5 V		±35	mA
I_{CC}	supply current			70	mA
I_{GND}	ground current		-70		mA
P_{tot}	total power dissipation	Tamb = -40 °C to + 125 °C		500	mW
T_{stg}	storage temperature		-65	+150	°C

8. Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. EnergyMath does not recommend exceeding them or designing to Absolute Maximum Ratings.

Table 6. Recommended Operating Conditions

Symbol	Parameter	Conditions	74HC573			74HCT573			Unit
			Min	Min	Typ	Min	Min	Typ	
V_{CC}	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
V_I	input voltage		0		V_{CC}	0		V_{CC}	V
V_O	output voltage		0		V_{CC}	0		V_{CC}	V
T_{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\triangle t/\triangle V$	input transition rise and fall rate	V_{CC} = 2.0 V			625				ns/V
		V_{CC} = 4.5 V		1.67	139		1.67	139	ns/V
		V_{CC} = 6.0 V			83				ns/V

9. Static Characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ[1]	Max	Min	Max	
74HC573								
V_{IH}	HIGH-level input voltage	V_{CC} = 3.0 V	2.0			2.0		V
		V_{CC} = 4.5 V	3.15			3.15		V
		V_{CC} = 6.0 V	4.2			4.2		V
V_{IL}	LOW-level input voltage	V_{CC} = 3.0 V			0.6		0.6	V
		V_{CC} = 4.5 V			1.35		1.35	V
		V_{CC} = 6.0 V			1.8		1.8	V
V_{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		I_O = -20μA; V_{CC} = 3.0 V	2.9			2.9		V
		I_O = -20μA; V_{CC} = 4.5 V	4.4			4.4		V
		I_O = -20μA; V_{CC} = 6.0 V	5.9			5.9		V
		I_O = -6.0 mA; V_{CC} = 4.5 V	3.84			3.7		V
		I_O = -7.8 mA; V_{CC} = 6.0 V	5.34			5.2		V
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		I_O = 20μA; V_{CC} = 3.0 V			0.1		0.1	V
		I_O = 20μA; V_{CC} = 4.5 V			0.1		0.1	V
		I_O = 20μA; V_{CC} = 6.0 V			0.1		0.1	V
		I_O = 6.0 mA; V_{CC} = 4.5 V			0.33		0.4	V
		I_O = 7.8 mA; V_{CC} = 6.0 V			0.33		0.4	V
I_I	input leakage current	$V_I = V_{CC}$ or GND ; V_{CC} = 6.0 V			±1		±1	μA
I_{OZ}	OFF-state output current	$V_I = V_{IH}$ or V_{IL} ; V_{CC} = 6.0V ; $V_O = V_{CC}$ or GND			±5		±10	μA
I_{CC}	supply current	$V_I = V_{CC}$ or GND ; I_O = 0A ; V_{CC} = 6.0 V			20		40	μA
C_I	input capacitance			6.5				pF

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ[1]	Max	Min	Max	
74HCT573								
V_{IH}	HIGH-level input voltage	V_{CC} = 3.0 V	2.0			2.0		V
		V_{CC} = 4.5 V	2.0			2.0		V
		V_{CC} = 5.5 V	2.0			2.0		V
V_{IL}	LOW-level input voltage	V_{CC} = 3.0 V			0.6		0.6	V
		V_{CC} = 4.5 V			0.8		0.8	V
		V_{CC} = 5.5 V			0.8		0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}						
		I_O = -20µA; V_{CC} = 3.0 V	2.9			2.9		V
		I_O = -20µA; V_{CC} = 4.5 V	4.4			4.4		V
		I_O = -6.0 mA; V_{CC} = 4.5 V	3.84			3.7		V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}						
		I_O = 20µA; V_{CC} = 3.0 V			0.1		0.1	V
		I_O = 20µA; V_{CC} = 4.5 V			0.1		0.1	V
		I_O = 6.0 mA; V_{CC} = 4.5 V			0.33		0.4	V
I_I	input leakage current	V_I = V_{CC} or GND ; V_{CC} = 5.5 V			±1		±1	µA
I_{OZ}	OFF-state output current	V_I = V_{IH} or V_{IL} ; V_{CC} = 5.5 V ; V_O = V_{CC} or GND			±5		±10	µA
I_{CC}	supply current	V_I = V_{CC} or GND ; I_O = 0 A ; V_{CC} = 5.5 V			20		40	µA
ΔI_{CC}	additional supply current	per pin ; V_I = V_{CC} - 2.1 V; I_O = 0 A; other inputs at V_{CC} or GND; V_{CC} = 4.5 V to 5.5 V			450		490	µA
C_I	input capacitance			6.5				pF

[1]All typical values are measured at T_{amb} = 25°C.

10. Dynamic Characteristics

Table 7. Dynamic characteristics
Voltages are referenced to GND (ground = 0 V); for test circuit see Fig. 10.

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ[1]	Max	Min	Max	
74HC573								
t_{pd}	propagation delay	Dn to Qn; see Fig. 6 [2]						
		V_{CC} = 3.0 V			30		35	ns
		V_{CC} = 4.5 V			20		25	ns
		V_{CC} = 6.0 V			15		18	ns
		LE to Qn; see Fig. 7 [3]						
		V_{CC} = 3.0 V			45		50	ns
		V_{CC} = 4.5 V			25		30	ns
		V_{CC} = 6.0 V			20		25	ns
t_t	transition time	Qn; see Fig. 6						
		V_{CC} = 3.0 V			30		35	ns
		V_{CC} = 4.5 V			19		22	ns
		V_{CC} = 6.0 V			16		19	ns
t_{en}	enable time	$\overline{OE}$ to Qn; see Fig. 8 [3]						
		V_{CC} = 3.0 V			22		25	ns
		V_{CC} = 4.5 V			14		17	ns
		V_{CC} = 6.0 V			13		16	ns
t_{dis}	disable time	$\overline{OE}$ to Qn; see Fig. 8 [4]						
		V_{CC} = 3.0 V			22		25	ns
		V_{CC} = 4.5 V			15		18	ns
		V_{CC} = 6.0 V			13		15	ns
t_W	pulse width	LE HIGH; see Fig. 7						
		V_{CC} = 3.0 V	25			30		ns
		V_{CC} = 4.5 V	19			22		ns
		V_{CC} = 6.0 V	16			19		ns
t_{SU}	set up time	Dn to LE; see Fig.9						
		V_{CC} = 3.0 V	16			20		ns
		V_{CC} = 4.5 V	13			15		ns
		V_{CC} = 6.0 V	11			13		ns
t_h	hold time	Dn to LE; see Fig.9						
		V_{CC} = 3.0 V	3			3		ns
		V_{CC} = 4.5 V	3			3		ns
		V_{CC} = 6.0 V	3			3		ns

Octal D-type transparent latch; 3-state

Symbol	Parameter	Conditions		-40 °C to +85 °C			-40 °C to +125 °C		Unit
				Min	Typ[1]	Max	Min	Max	
C_{PD}	power dissipation capacitance	f_i = 1 MHz; V_I = GND to V_{CC}; [6]			115				pF
74HCT573									
t_{pd}	propagation delay	Dn to Qn; see Fig. 6 [2]							
		V_{CC} = 4.5 V				25		30	ns
		LE to Qn; see Fig. 7 [2]							
		V_{CC} = 4.5 V				25		30	ns
t_t	transition time	Qn; see Fig. 6 [5]							
		V_{CC} = 4.5 V				25		30	ns
t_{en}	enable time	$\overline{OE}$ to Qn; see Fig. 8 [3]							
		V_{CC} = 4.5 V				20		25	ns
t_{dis}	disable time	$\overline{OE}$ to Qn; see Fig. 8 [4]							
		V_{CC} = 4.5 V				20		25	ns
t_W	pulse width	LE HIGH; see Fig. 7							
		V_{CC} = 4.5 V		19			22		ns
t_{SU}	set up time	Dn to LE; see Fig.9							
		V_{CC} = 4.5 V		13			15		ns
t_h	hold time	Dn to LE; see Fig.9							
		V_{CC} = 4.5 V		3			3		ns
C_{PD}	power dissipation capacitance	f_i = 1 MHz; V_I = GND to V_{CC} − 1.5 V ; [6]			115				pF

[1] Typical values are measured at T_{amb} = 25 °C.

[2] t_{pd} is the same as t_{PLH} and t_{PHL}.

[3] t_{en} is the same as t_{PZL} and t_{PZH}.

[4] t_{dis} is the same as t_{PLZ} and t_{PHZ}.

[5] t_t is the same as t_{THL} and t_{TLH}.

[6] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:

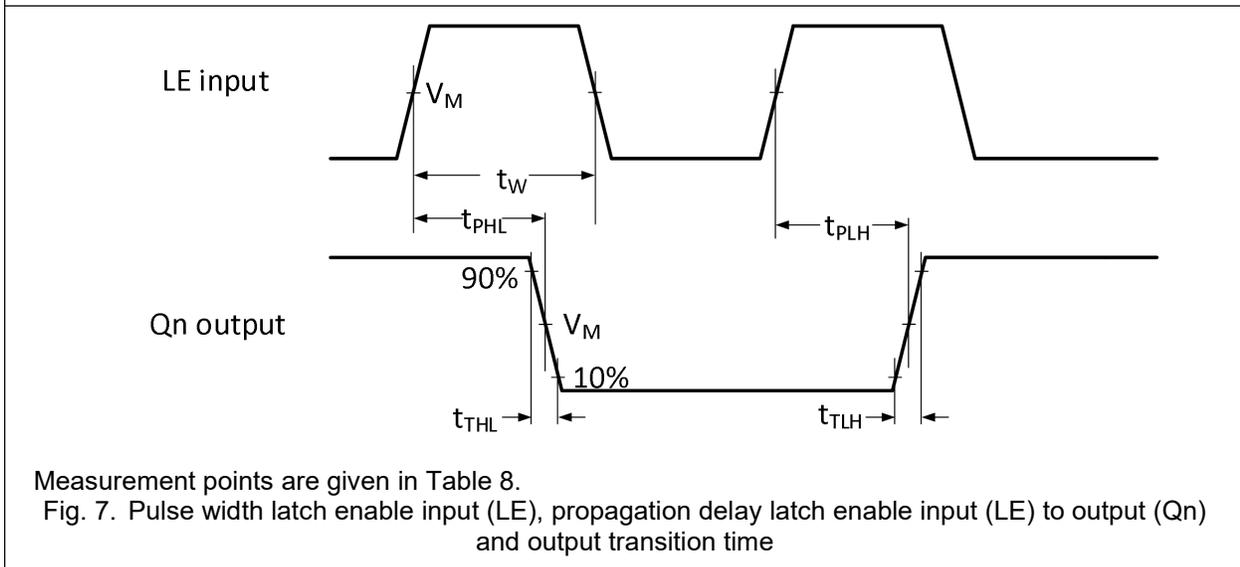f_i = input frequency in MHz;

f_o = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in V;

N = number of inputs switching;

$\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of outputs.

10.1. Waveforms and test circuit

Measurement points are given in Table 8.
Fig. 6.   Propagation delay data input (Dn) to output (Qn) and output transition time

Measurement points are given in Table 8.
Fig. 7. Pulse width latch enable input (LE), propagation delay latch enable input (LE) to output (Qn) and output transition time
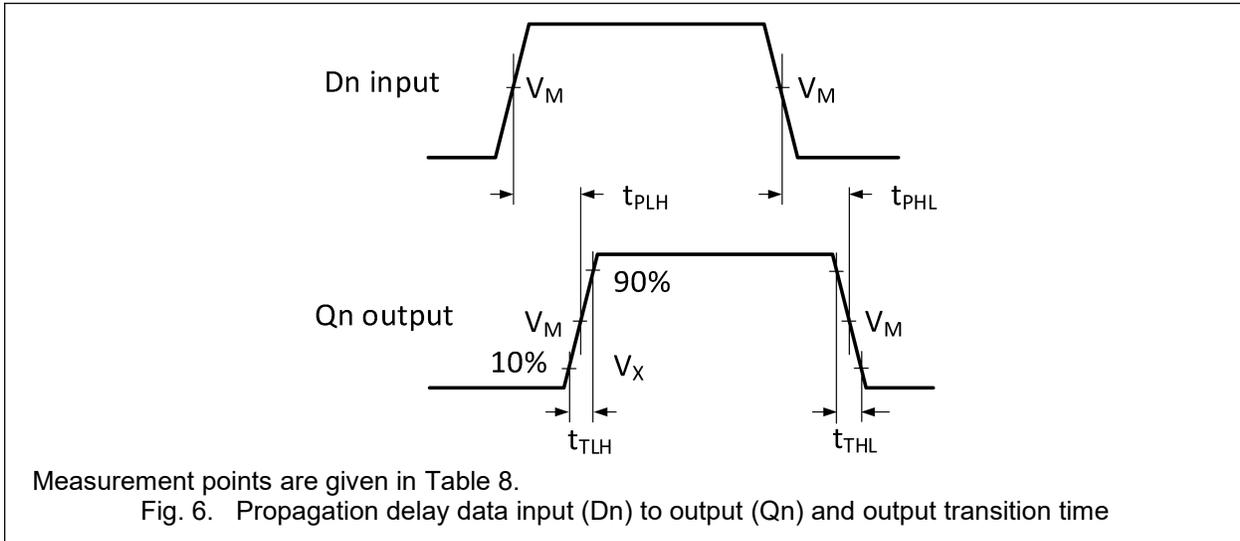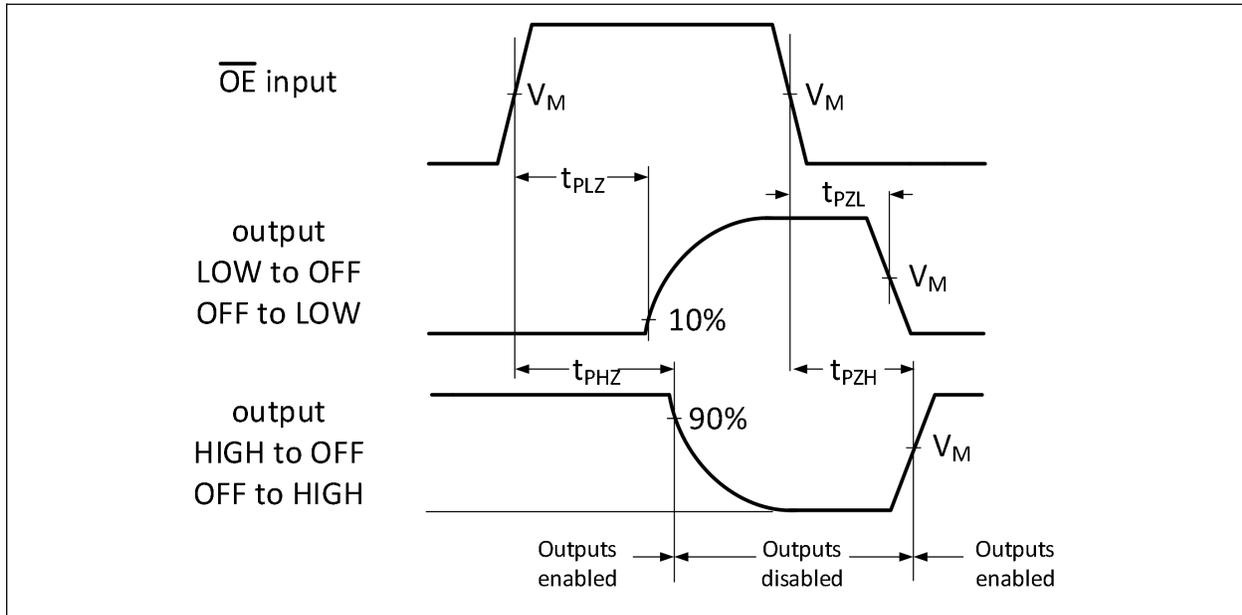
Measurement points are given in Table 8.
V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig. 8.   Enable and disable times
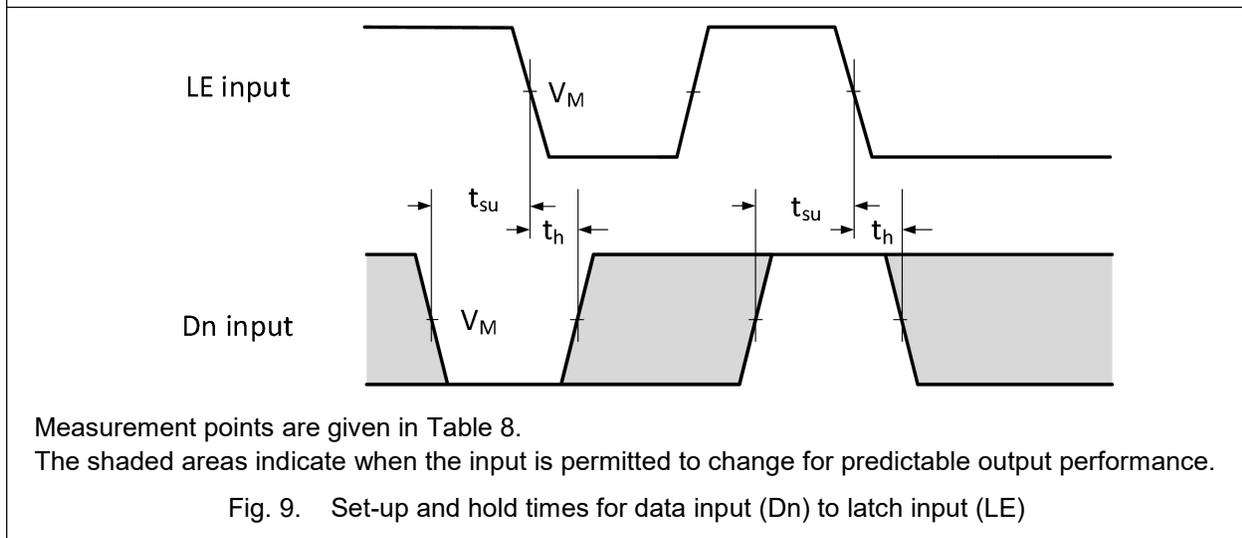
Measurement points are given in Table 8.
The shaded areas indicate when the input is permitted to change for predictable output performance.

Fig. 9.   Set-up and hold times for data input (Dn) to latch input (LE)

Table 8. Measurement points

Type	Input	Output
	V_M	V_M
74HC573	$0.5V_{CC}$	$0.5V_{CC}$
74HCT573	1.3 V	1.3 V

Test data is given in Table 9.
Definitions for test circuit:
R_L = Load resistance.
C_L = Load capacitance including jig and probe capacitance.
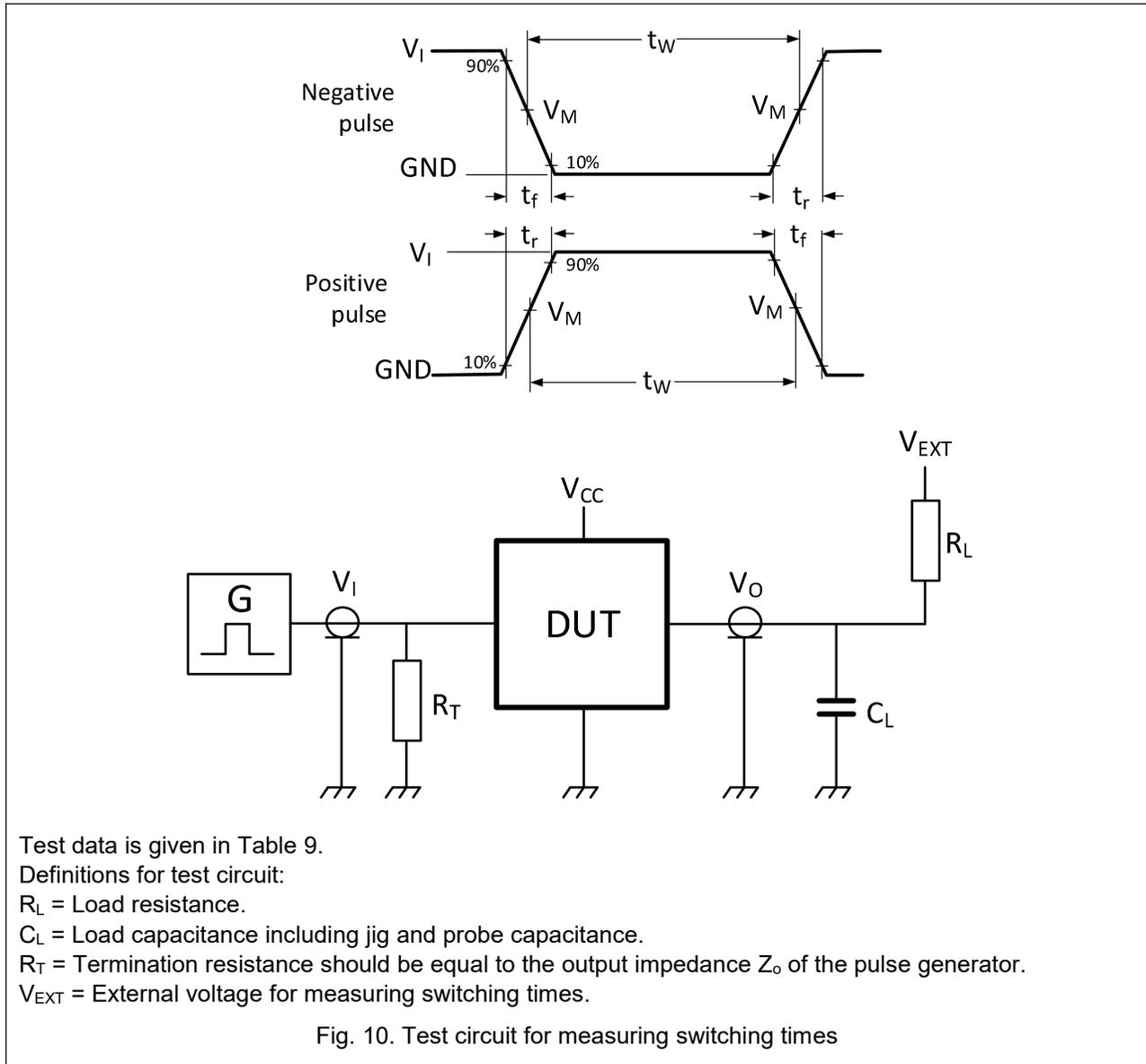R_T = Termination resistance should be equal to the output impedance Z_o of the pulse generator.
V_{EXT} = External voltage for measuring switching times.

Fig. 10. Test circuit for measuring switching times

Table 9. Test data

Type	Input		Load		V_{EXT}		
	V_I	$t_r = t_f$	C_L	R_L	t_{PZL}, t_{PLZ}	t_{PHL}, t_{PLH}	t_{PZH}, t_{PHZ}
74HC573	V_{CC}	2.5 ns	15 pF	500Ω	V_{CC}	Open	GND
74HCT573	3 V	2.5 ns	15pF	500Ω	V_{CC}	Open	GND

11. Package Outline

SOP-20L

Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min.	Max.		Min.	Max.
A	12.600	12.900	C4	0.246	0.262
A1	0.381	0.431	D	1.353	1.453
A2	1.240	1.300	D1	0.764	0.964
A3	0.450	0.460	D2	0.18TYP	
B	7.400	7.600	R1	0.30TYP	
B1	10.206	10.406	R2	0.20TYP	
C	2.150	2.300	θ1	12° TYP	
C1	0.938	1.038	θ2	12° TYP	
C2	0.938	1.2038	θ3	0° ~ 8°	
C3	0.145	0.205			

TSSOP-20L

Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min.	**Max.**		**Min.**	**Max.**
A	-	1.20	E	6.20	6.60
A1	0.05	0.15	e	0.65BSC	
A2	0.80	1.05	L	0.45	0.75
A3	0.39	0.49	L1	1.00REF	
b	0.20	0.28	θ	0°	8°
b1	0.19	0.25			
c	0.13	0.17			
c1	0.12	0.14			
D	6.40	6.60			
E1	4.30	4.50			

12. Abbreviations

Table 10. Abbreviations

Acronym	Description
CMOS	Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
CDM	Charged Device Model
TTL	Transistor-Transistor Logic

13. Revision History

Table 11. Revision history

Document ID	Release Date	Data sheet status	Change notice	Supersedes
74HC_HCT573 Rev. 1.0	Aug 08, 2024	Draft datasheet		